S	earch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
09/842,668	KOBAYASHI ET AL.
Examiner	Art Unit
Richard Lee	2613

	SEARCHED		
Class	Subclass	Date	Examiner
375	240.19	6/8/2005	RL
Updated	Search	6/8/2005	RL
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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